

Sample Results Summary Sheet

Please return this form to the Curator for each allocated Sample

Sample ID: RB-QD04-0047-02

PI: Masayuki Uesugi

Type and date of analysis performed:

FIB sectioning (Nov. 27, and 28, 2013)

Elements or phases identified: (Mg, Si, olivine, pyroxene, aromatic carbon, etc.)

N/A

Contaminant phases identified: (Al, SUS, carbon particles, etc.)

N/A

Sample handling: (e.g. exposed in atmosphere, embedded in resin, polished, sliced by FIB or UMT)

Pressed on Au plate (3mm diameter and 0.3mm thick) by Sapphire glass

Sectioned by Focused Ion Beam (FIB) (2 ultra-thin sections were extracted).

State of sample pre-analysis:

N2 hold. On Au coated sapphire glass.

State of sample post-analysis:

RB-QD04-0047-02:pressed on Au plate, partially sectioned by FIB, damaged by Ga beam, N2 hold in sample holder

RB-QD04-0047-02-01: UTS by FIB

RB-QD04-0047-02-02: UTS by FIB, lost during FIB manipulation

Analysis data Notes: (summary of the attached analysis data and/or images)

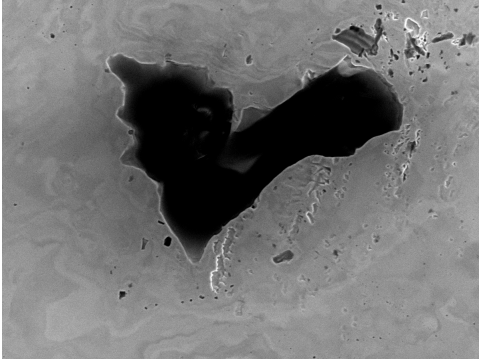


Fig.1 Backscattered electron of RB-QD04-0047-02 after pressing on Au plate

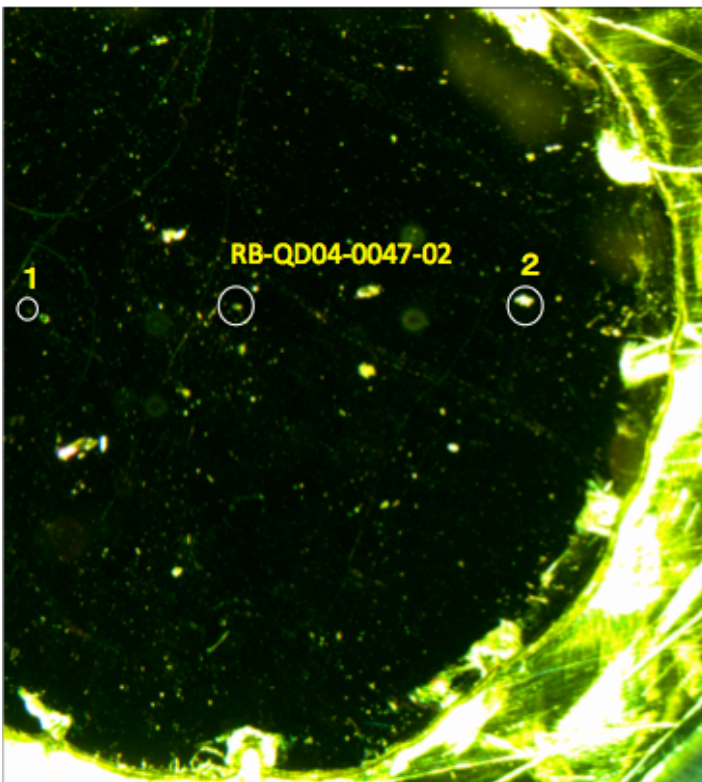


Fig. 2 Whole view of Au plate. Standards for NanoSIMS analysis were also pressed on the Au plate (1 and 2). The Au plate was pressed and fixed on a half-inch stab holder.

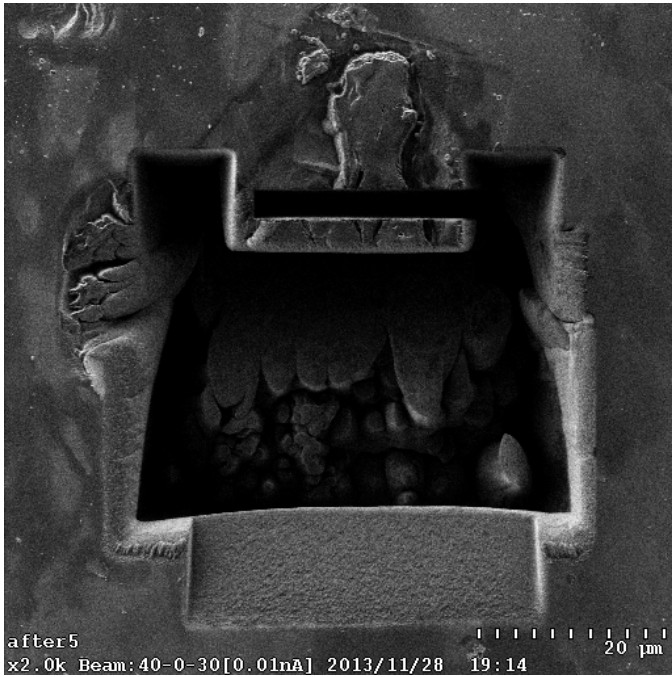


Fig. 3 SIM image of extraction of RB-QD04-0047-02-01 by FIB fabrication (final condition of RB-QD04-0047-02).